

DHM® R1100 series

The ultimate optical profiler with sub-nanometer resolution and no vertical scanning needed up to 10 μm

Lyncée Tec's DHM R1100 series of reflection configured high precision optical profilers offers the ultimate technology based on Digital Holographic Microscopy. It keeps the features, the versatility and ease-of-use of the DHM R1000 series. In addition to the single wavelength mode that gives these instruments the same real-time performances, the DHM R1101 and R1102 have two additional operating modes:

- the alternate dual wavelength mode for fast measurements of steps up to 10 µm and smooth samples up to the objective's depth of field
- the vertical coherence scanning mode for vertical dimensions up to 10 mm

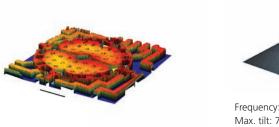
DHM R1100 series is compatible with the optional Lyncée Tec stroboscopic module for intuitive investigation of MEMS / MOEMS. The signal generator is integrated into the module, allowing the powerful Koala software to drive your sample and synchronize the acquisition in order to retrieve its full-field topography along the complete cycle, in a similar way to the real-time mode.

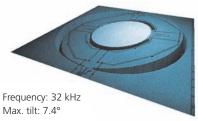
The off-axis holographic principle ensures the vertical calibration is only determined by the wavelength. No mechanical movement needs to be calibrated. DHM's single and dual wavelength modes are thus the optical profiler modes with the least systematic error sources on the market. DHM thus not only ensures high accuracy, but also ultimate precision.

The DHM R1100 series is composed of two models:

- the DHM R1101 may be fitted with manual or motorized stages up to 150 mm × 150 mm travel range for sample with dimension up to 415 mm
- the DHM R1102 may be fitted with larger motorized stages up to 300 mm × 300 mm travel range for samples with dimensions up to 530 mm × 870 mm

The R1101 can be upgraded to the R1102.







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Technical specifications

System	
Measurement techniques:	single and dual wavelength digital holographic microscopy in reflection and
	vertical coherence scanning
Image types:	intensity and quantitative phase contrast image (DHM mode), optical topography (vertical
	scanning)
Light sources:	two monochromatic laser sources
Sample stage:	manual or automated XYZ stages up to $300 \times 300 \times 12.5$ mm travel range
Camera:	1392 × 1040 pixels, 8 bits
Available objectives:	standard, high NA, long working distance, water/oil immersion microscope objectives
Objective mounting:	4-position turret
Computer:	Dell workstation with latest Intel [®] processor, optimized and configured for DHM,
	with 19" SXGA monitor
Software:	Lyncée Tec proprietary Koala classic software based on C++ and .NET
Optional working mode:	stroboscopic mode
Performance	
Measurement mode:	Single wavelength Dual wavelength Vertical scanning
Accuracy ¹ :	0.1 nm 25 nm (0.1 nm) ⁴ 0.5 μm
Vertical resolution ² :	0.2 nm 50 nm (0.2 nm) ⁴ 1.0 μm
Repeatability ³ :	$< 0.01 \text{ nm}$ 0.25 nm (< 0.01 nm) ⁴ < 0.05 μ m
Vertical calibration:	determined by the wavelength, no mechanical movement calibration
Vertical measuring range in single wavelength:	up to depth of field for smooth samples, up to 340 nm for sharp edge samples
Vertical measuring range in dual wavelength:	up to depth of field for smooth samples, up to 10 µm for sharp edge samples
Vertical measuring range in vertical scanning:	up to 10 mm, z-stage dependent
Lateral resolution:	objective dependent, down to 300 nm with oil immersion objectives (1.4 NA)
Field of view:	objective dependent, up to 4.4 mm
Working distance:	objective dependent, from 0.3 to 18 mm
Digital focusing range:	up to 50× depth of field (objective dependent)
Grabbing time (1 hologram):	down to 1 µs in a single image grab 1024 × 1024 pixels (hologram)
Spatial sampling: Acquisition rate:	15 fps (1024 × 1024 pixels) (optional up to 300 fps)
Single wavelength reconstruction rate:	$15 \text{ fps} (1024 \times 1024 \text{ pixels}) (optional up to 500 \text{ ps})$ 15 fps (512 × 512 pixels), 4 fps (1024 × 1024 pixels)
Dual wavelength acquisition time:	1.5 s
Vertical scanning acquisition time:	scanning speed: 6 μm/s, reconstruction time: 6 s
Min. sample reflectivity:	less than 1%
Sample illumination:	down to 1 µW/cm ²
Power requirements	Sector Se
Input voltage:	85-260 VAC - 50/60 Hz
Power requirements (w/o computer):	max. 480 W
Dimensions & weight	5111 * S 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5
Microscope:	R1101 R1102
Dimensions ($L \times W \times H$):	600 × 600 × 800 mm 900 × 900 × 850 mm
Weight:	45 kg 80 kg
Maximum sample size $(L \times W)$:	∞ x 415 mm 530 x 870 mm

¹ As demonstrated by taking the temporal standard deviation on 1 pixel over 30 measurements*.

² Defined as twice the accuracy.

³ As demonstrated by taking the one sigma Rq value of 30 repeatability measurements* on SiC reference mirror.

⁴ When combined to single wavelength measurements.

* For single wavelength, 1 measurement is the average of 10 acquisitions.

